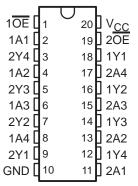
SCAS293A - JANUARY 1993 - REVISED JULY 1995

- EPIC<sup>™</sup> (Enhanced-Performance Implanted CMOS) Submicron Process
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   < 0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Latch-Up Performance Exceeds 250 mA Per JEDEC Standard JESD-17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages

### DB, DW, OR PW PACKAGE (TOP VIEW)



#### description

This octal buffer/driver is designed for 2.7-V to 3.6-V V<sub>CC</sub> operation.

The SN74LVC240 is designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

The SN74LVC240 is organized as two 4-bit buffers/drivers with separate output-enable  $(\overline{OE})$  inputs. When  $\overline{OE}$  is low, the device passes data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVC240 is characterized for operation from -40°C to 85°C.

### FUNCTION TABLE (each buffer)

INP	JTS	OUTPUT			
OE	Α	Y			
L	Н	L			
L	L	Н			
Н	Χ	Z			

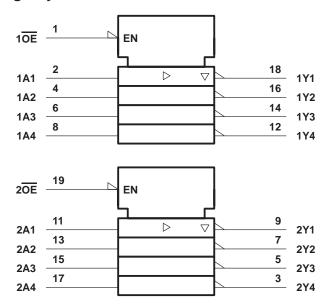


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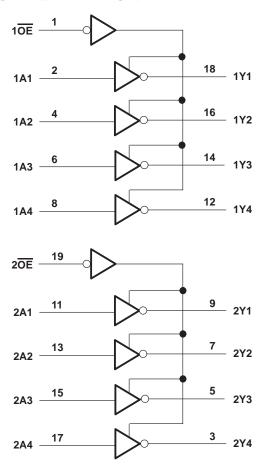


#### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive logic)



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. This value is limited to 4.6 V maximum.
  - 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the Package Thermal Considerations application note in the 1994 ABT Advanced BiCMOS Technology Data Book, literature number SCBD002B.



#### recommended operating conditions (see Note 4)

		MIN	MAX	UNIT
Vcc	Supply voltage	2.7	3.6	V
VIH	High-level input voltage $V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		V
$V_{IL}$	Low-level input voltage $V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8	V
٧ <sub>I</sub>	/ <sub>I</sub> Input voltage			V
٧o	Output voltage	0	VCC	V
ЮН	$V_{CC} = 2.7 \text{ V}$		-12	mA
	High-level output current  VCC = 3 V		-24	IIIA
lOL	V <sub>CC</sub> = 2.7 V		12	mA
	Low-level output current VCC = 3 V		24	IIIA
Δt/Δν	Input transition rise or fall rate	0	10	ns/V
T <sub>A</sub>	Operating free-air temperature	-40	85	°C

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDI	TIONS	v <sub>cc</sub> †	MIN	TYP‡	MAX	UNIT	
Voн	$I_{OH} = -100 \mu\text{A}$		MIN to MAX	V <sub>CC</sub> −0.	2			
	I <sub>OH</sub> = - 12 mA		2.7 V	2.2			V	
			3 V	2.4			V	
			3 V	2				
VOL	I <sub>OL</sub> = 100 μA		MIN to MAX			0.2		
	$I_{OL} = 12 \text{ mA}$ 2.7 V				0.4	V		
	I <sub>OL</sub> = 24 mA		3 V			0.55	]	
lį	V <sub>I</sub> = 5.5 V or GND		3.6 V			±5	μΑ	
loz	$V_O = V_{CC}$ or GND		3.6 V			±10	μΑ	
lcc	$V_I = V_{CC}$ or GND,	) = 0	3.6 V			20	μΑ	
∆l <sub>CC</sub>	One input at V <sub>CC</sub> – 0.6 V,	other inputs at V <sub>CC</sub> or GND	3 V to 3.6 V			500	μΑ	
C <sub>i</sub>	$V_I = V_{CC}$ or GND		3.3 V		5.5		pF	
Co	$V_O = V_{CC}$ or GND	-	3.3 V		5.8		pF	

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate values under recommended operating conditions.

# switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 2.7 V		UNIT
			MIN	MAX	MIN	MAX	
t <sub>pd</sub>	А	Y	1.5	7.5		8.5	ns
t <sub>en</sub>	ŌĒ	Υ	1.5	8		9	ns
<sup>t</sup> dis	ŌĒ	Y	1.5	7.5		8.5	ns

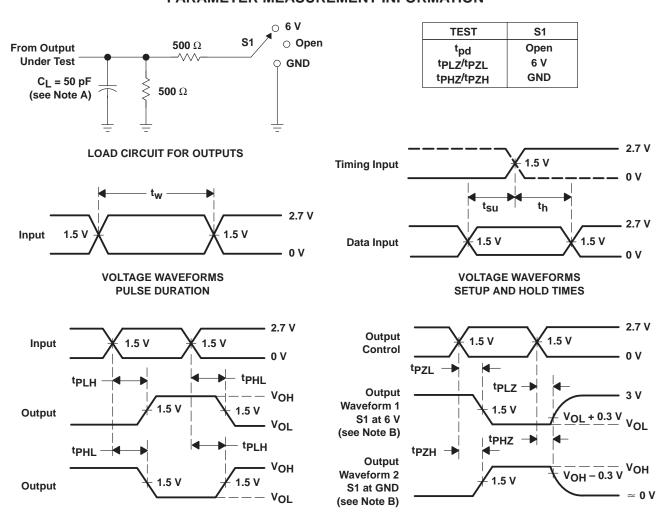


<sup>&</sup>lt;sup>‡</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

#### operating characteristics, $V_{CC} = 3.3 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

PARAMETER			TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance per buffer/driver	Outputs enabled	C <sub>1</sub> = 50 pF, f = 10 MHz	24	nE	
	Outputs disabled	$C_L = 50  \text{pr},  \Gamma = 10  \text{MHz}$	2.5	pr	

#### PARAMETER MEASUREMENT INFORMATION



**VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES** INVERTING AND NONINVERTING OUTPUTS

**VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES LOW- AND HIGH-LEVEL ENABLING** 

NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f \leq 2.5 \ ns$ ,  $t_f \leq 2.5 \ ns$ .
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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